

**Search Notes****Application/Control No.**

10/586,239

**Examiner**

HANH N. NGUYEN

**Applicant(s)/Patent under  
Reexamination**

SHIKAYAMA ET AL.

**Art Unit**

2834

**SEARCHED**

Class	Subclass	Date	Examiner
310	12	6/6/2008	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR